

## Low-temperature charge-density-wave dynamics and switching in NbSe<sub>3</sub>

T. L. Adelman, J. McCarten, M. P. Maher, D. A. DiCarlo, and R. E. Thorne

Laboratory of Atomic and Solid State Physics and Materials Science Center, Cornell University, Ithaca, New York 14853

(Received 19 May 1992; revised manuscript received 28 October 1992)

We have studied charge-density-wave (CDW) transport in NbSe<sub>3</sub> at temperatures below 45 K. Between the threshold electric field  $E_T$  and a second characteristic field  $E_T^*$ , the CDW conductivity varies as  $\sigma_{\text{CDW}} \propto \exp(-\Delta/k_B T)$ , with an activation energy  $\Delta$  comparable to the CDW gap. Above  $E_T^*$ , the CDW conductivity increases, in many crystals via an abrupt "switch," to a much larger, only weakly temperature-dependent value. Contrary to previous suggestions, we find that  $E_T^*$  is determined by bulk CDW pinning and dynamics, not by isolated defects. We show that this behavior has strong analogs in the semiconducting CDW materials, and compare it with predictions based upon a model of CDW-normal-carrier interactions proposed by Littlewood.

For applied electric fields greater than a threshold field  $E_T$ , charge-density waves (CDW's) can depin from impurities and transport charge.<sup>1</sup> In NbSe<sub>3</sub>, two independent CDW's form at temperatures of  $T_{P_1} = 145$  K and  $T_{P_2} = 59$  K. For the  $T_{P_1}$  CDW at temperatures between  $T_{P_1}$  and  $T_{P_2}$  and for the  $T_{P_2}$  CDW at temperatures down to  $\sim 40$  K, the onset of CDW conduction at  $E_T$  is smooth, and the CDW current increases continuously as the field is increased. Below  $T \approx 40$  K, the  $I$ - $V$  characteristic changes qualitatively. Many crystals exhibit "switching,"<sup>2</sup> where the CDW current jumps discontinuously from zero to some finite value at a threshold  $E_T^s$ .

Previous studies<sup>2-6</sup> of switching in NbSe<sub>3</sub> have indicated that (1)  $E_T^s$  is approximately independent of temperature;<sup>3</sup> (2) switching at  $E_T^s$  is often hysteric and is often accompanied by large-amplitude low-frequency noise;<sup>2-4</sup> (3) at fields above  $E_T^s$ , the differential resistance  $dV/dI$  is approximately constant;<sup>3</sup> (4) switching is observed in only a fraction of NbSe<sub>3</sub> crystals, and this fraction can be increased by iron doping<sup>4</sup> or quenching;<sup>5</sup> and (5) in some crystals, regions having different switching thresholds  $E_T^s$  are arranged serially, with sharply defined boundaries between these regions.<sup>3,6</sup>

Motivated by observation (5) above, Hall and co-workers<sup>3,6</sup> proposed that switching in NbSe<sub>3</sub> is due to localized, ultrastrong pinning centers which necessitate phase slip at the pinning site; detailed models based upon this idea have been given by Inui *et al.* and Marcus, Strogatz, and Westervelt.<sup>7</sup> Other models invoking phase slip and/or serial coupling of CDW domains have also been proposed.<sup>8</sup>

Here we present an alternative view of low-temperature transport in NbSe<sub>3</sub>. We show that switching is an intrinsic effect and thus that isolated defects are not its primary cause. More importantly, we find that the general characteristics of low-temperature CDW conduction in both switching and nonswitching NbSe<sub>3</sub> crystals are highly analogous to those observed in semiconducting CDW materials such as K<sub>0.3</sub>MoO<sub>3</sub>. We show that these characteristics are qualitatively consistent with predictions based upon a model of CDW-normal-carrier in-

teractions proposed by Littlewood,<sup>9</sup> and we discuss the applicability of this model to NbSe<sub>3</sub>.

We begin by describing experiments to investigate the origin of switching. Figure 1 shows four-probe data for the normal depinning threshold  $E_T$  at  $T = 50$  K and the switching threshold  $E_T^s$  at  $T = 25$  K versus inverse crystal thickness, for NbSe<sub>3</sub> crystals from a single high-purity ( $r_R > 300$ ) growth. Both thresholds vary approximately linearly with inverse crystal thickness for thicknesses up to  $\sim 10 \mu\text{m}$ , and the average ratio  $E_T^s(25 \text{ K})/E_T(50 \text{ K})$  is approximately 16.

The normal depinning threshold  $E_T$  is determined by CDW pinning by impurities distributed throughout the crystal volume. The increase in  $E_T$  with decreasing thickness results because the bulk [three-dimensional (3D)] CDW correlation length in the thickness direction is comparable to or larger than the thickness of most un-

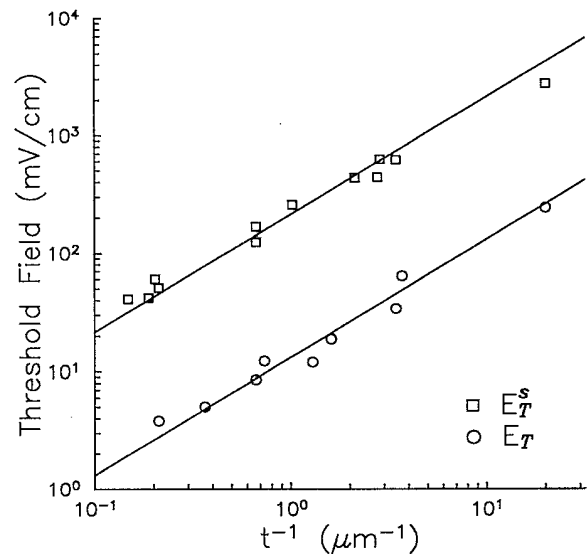


FIG. 1. Normal depinning electric field  $E_T$  at  $T = 50$  K and switching field  $E_T^s$  at  $T = 25$  K vs inverse crystal thickness for undoped NbSe<sub>3</sub>. Both fields vary inversely with thickness (solid lines).

doped NbSe<sub>3</sub> crystals;<sup>10</sup> CDW pinning thus has a 2D character,<sup>11</sup> for which  $E_T \propto t^{-1}$  is predicted. Since  $E_T^s$  and  $E_T$  show a similar thickness dependence and a similar scatter from the average behavior, Fig. 1 indicates that  $E_T^s$  is also determined by CDW pinning and dynamics throughout the crystal volume.

Figure 2 shows the electric field versus total current at  $T=23$  K for three different segments of the same crystal. The measurements were performed with the current leads interior to the voltage leads to ensure that each segment was depinned independently. All segments show a single switch at nearly identical currents and electric fields  $E_T^s$ . Thickness-related  $E_T^s$  variations indicated in Fig. 1 make the odds of randomly selecting two crystals with comparably close  $E_T^s$  values much less than 1 in 1000. Similar measurements have been performed on 47 segments from 13 crystals. Of these, 36 segments showed a single switch. For 21 of the 33 pairs of adjacent segments,  $E_T^s$  values agreed to within 2.5%, and only two pairs had  $E_T^s$  values differing by more than 25%. These results, together with those of Fig. 1, provide strong evidence that switching is an intrinsic effect, and that the magnitude of  $E_T^s$  is determined within the crystal volume.

The results of Figs. 1 and 2 are inconsistent with models<sup>3,6,7</sup> in which switching arises from phase slip at isolated strong-pinning defects. Such models predict large crystal-to-crystal and segment-to-segment variations in  $E_T^s$ , and cannot explain the simple scaling of  $E_T$  and  $E_T^s$  with crystal thickness. Moreover, such models are implausible quantitatively. Measurements by Gill, Monceau *et al.*, and Maher *et al.*<sup>12</sup> and the theory of Ramakrishna *et al.*<sup>13</sup> indicate that the voltage required to produce phase slip at electrical contacts is independent of contact separation, impurity concentration, and (to first approximation) crystal thickness, but is strongly

temperature dependent. For millimeter-long samples, the measured phase-slip voltages correspond to electric fields one to four orders of magnitude smaller than typical  $E_T^s$  values. Phase slip at isolated defects should, if anything, require even smaller voltages. While it is clear from previous work<sup>3,5,6</sup> that some NbSe<sub>3</sub> crystals are segmented into regions with different  $E_T^s$  values and different CDW current densities,<sup>14</sup> the phase slip which must occur between these regions cannot be the underlying cause of switching, and cannot determine the characteristic magnitude of  $E_T^s$ .

Switching is not observed in many NbSe<sub>3</sub> crystals. Therefore, more fundamental to understanding low-temperature CDW transport are those features which are observed in all crystals. Figure 3 shows typical differential resistance versus electric field data at temperatures between 41 and 23 K, for a single undoped NbSe<sub>3</sub> crystal. For  $T < 40$  K, CDW conduction above  $E_T$  separates into two regions: (1) Between  $E_T$  and a second characteristic field  $E_T^*$ , the CDW conductivity is strongly temperature dependent and vanishes at low temperatures; and (2) above  $E_T^*$ , the CDW conductivity is large and only weakly temperature dependent.  $E_T^*$  is nearly independent of temperature, while  $E_T$  increases gradually with decreasing temperature. At low temperatures where the CDW conductivity is very small,  $E_T$  is indicated by a change in the normal-carrier resistivity due to CDW polarizations. This general behavior is observed in *all* undoped NbSe<sub>3</sub> crystals, including those which do not switch. In crystals which do switch,  $E_T^*$  evolves into  $E_T^s$  at low temperatures.

Figure 4 shows the CDW conductivity at  $E \approx 0.95E_T^*$  vs  $1/T$  for three NbSe<sub>3</sub> crystals. As indicated by the solid lines, the CDW conductivity is activated, i.e.,  $\sigma_{CDW} \sim \exp(-\Delta/k_B T)$ , with an activation energy

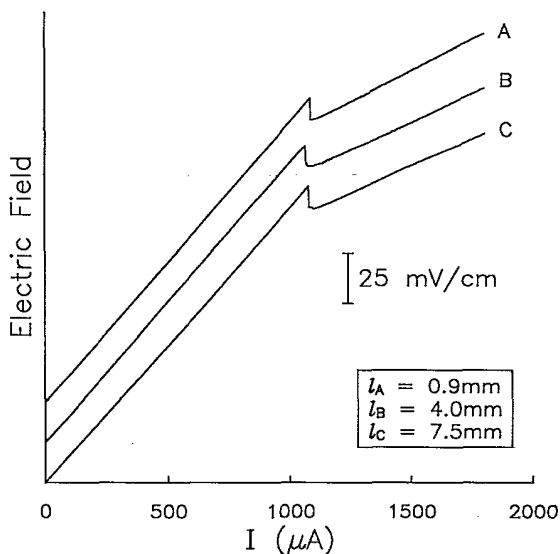


FIG. 2. Electric field vs total current at  $T=23$  K for three different segments of the same undoped NbSe<sub>3</sub> crystal. Switching is observed at nearly identical fields and currents in all three segments.

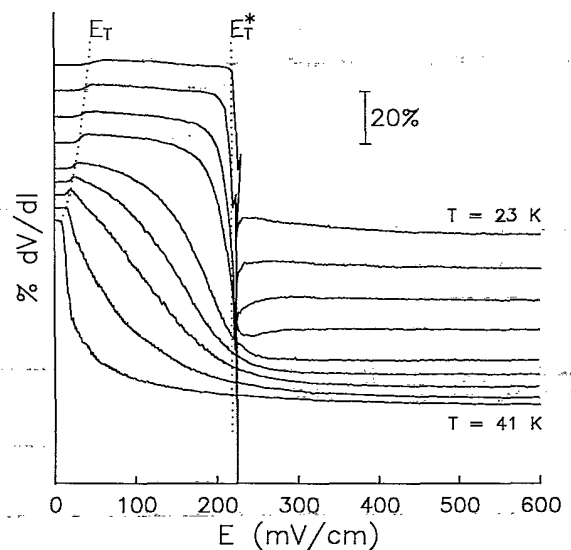


FIG. 3. Differential resistance  $dV/dI$  vs electric field for a single undoped NbSe<sub>3</sub> crystal at temperatures of 41, 38, 35, 33, 31, 28, 26, 25, and 23 K. CDW conduction between  $E_T$  and  $E_T^*$  decreases rapidly with decreasing temperature, whereas conduction above  $E_T^*$  is nearly independent of temperature.

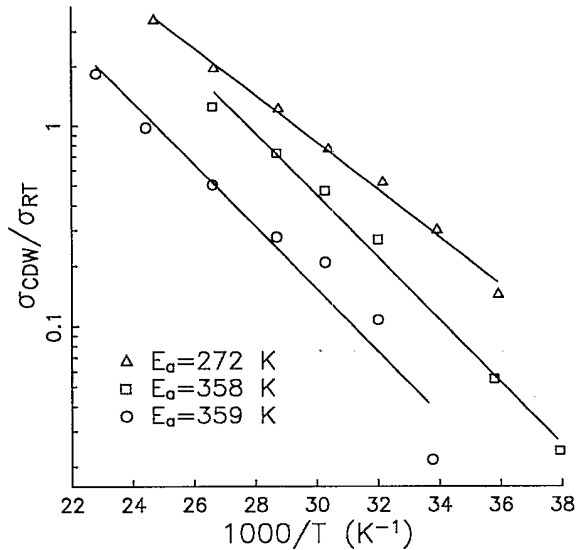


FIG. 4. CDW conductivity (normalized by the room-temperature conductivity) measured at  $E \approx 0.95E_T^*$  for three different undoped NbSe<sub>3</sub> crystals. The solid lines represent fits of the form  $\sigma_{CDW} \propto \exp(-E_d/k_B T)$ .

$\Delta \approx 330$  K. This energy is comparable to half the  $T_{P_2}$  CDW gap energy determined from tunneling measurements.<sup>15</sup>

The behavior shown in Figs. 3 and 4 is strikingly similar to that observed in the semiconducting CDW materials  $K_{0.3}MoO_3$ , TaS<sub>3</sub>, and  $(TaSe_4)_2I$ .<sup>16</sup> In these materials, the CDW conductivity  $\sigma_{CDW}$  above  $E_T$  scales with the normal conductivity  $\sigma_n$  of the thermally excited quasiparticles. Both are activated,  $\sigma_{CDW} \propto \sigma_n \sim \exp(-\Delta/k_B T)$ , with an activation energy  $\Delta$  comparable to half the CDW gap. At temperatures below  $\sim T_P/3$ , the CDW conductivity is observed to increase dramatically above a characteristic field  $E_T^*$  roughly two orders of magnitude larger than  $E_T$ . In many crystals at sufficiently low temperatures, the transition from the low- to high-conductivity state occurs via switching.

Littlewood<sup>9</sup> has investigated low-temperature CDW conduction in the semiconducting materials by including the effects of CDW-normal-carrier interactions within the Fukuyama-Lee-Rice model. In this model, charge fluctuations associated with CDW deformations drive normal-carrier screening currents, and dissipation associated with these currents leads to a velocity (frequency)-dependent damping coefficient for the CDW. For CDW velocities corresponding to drift frequencies  $\omega_d < \omega_d^* \propto \sigma_n$ , the damping is inversely proportional to the normal-carrier conductance  $\sigma_n$ , resulting in a scaling between the CDW and normal conductivities. For drift frequencies  $\omega_d > \omega_d^*$ , normal-carrier screening is no longer effective, the damping decreases to a value determined by other processes, and the CDW conductivity increases. At sufficiently low temperatures, the decrease in damping at  $\omega_d^*$  is dramatic and leads to bistability and switching in the  $I$ - $V$  characteristic. Thus, this model predicts two characteristic fields  $E_T$  and  $E_T^* \propto \omega_d^*/\sigma_{CDW}$ ; a scaling  $\sigma_{CDW} \propto \sigma_n$  for  $E_T < E < E_T^*$ ; a much larger, weak-

ly temperature-dependent CDW conductance above  $E_T^*$ ; switching at  $E_T^*$  at low temperatures; and since  $\omega_d^*$  and  $\sigma_{CDW}(E < E_T^*)$  are both proportional to  $\sigma_n$ , a weakly temperature dependent  $E_T^*$ . These predictions are all qualitatively consistent with observations in the semiconducting materials.<sup>17</sup>

These qualitative predictions are also consistent with most observations in NbSe<sub>3</sub>, with one serious exception: the normal-carrier conductance  $\sigma_n$  in NbSe<sub>3</sub> increases with decreasing temperature in the temperature range where the CDW conductance below  $E_T^*$  is rapidly decreasing. Unlike the semiconducting materials, a small part ( $\sim 10^{-4}$ ) of NbSe<sub>3</sub>'s Fermi surface remains ungapped at low temperatures.<sup>18</sup>  $\sigma_n$  increases at low temperatures, in spite of a dramatic decrease in the normal-carrier density, because of an equally dramatic increase in the mobility of the remaining carriers. Littlewood's model of low-temperature transport might still apply to NbSe<sub>3</sub> if thermally excited quasiparticles on gapped portions of the Fermi surface were primarily responsible for CDW damping. Why this should be the case is unclear, but the activated form of the CDW conductance below  $E_T^*$  and the magnitude of the activation energy are consistent with this idea.

Littlewood's approximate analytic treatment also makes a quantitative prediction: that the crossover in CDW damping should occur at a CDW drift frequency equal to the dielectric relaxation frequency, i.e., at  $\omega_d^* = \omega_r \equiv \sigma_n/\epsilon$ . This prediction is in dramatic disagreement with experiment. From our data for NbSe<sub>3</sub>, the measured  $\sigma_n$  values together with the assumption  $\epsilon = 10\epsilon_0$  yield  $\omega_d^*/(2\pi)$  values of  $2.3 \times 10^{15}$  and  $3.3 \times 10^{15}$  Hz at  $T = 35$  and  $28$  K, respectively. If the Ohmic conductance due to thermally excited quasiparticles  $\sigma_n^{qp}$  is assumed to determine  $\omega_d^*$ , then estimates obtained by scaling  $\sigma_n(T_{P_2})$  with  $\sigma_n(T)$  for the semiconducting CDW materials yield drift frequencies of  $6.8 \times 10^{13}$  and  $2.3 \times 10^{13}$  Hz, respectively. In contrast, the  $\omega_d/(2\pi)$  values measured at  $E \approx 0.95E_T^*$  are  $2.9 \times 10^7$  and  $3.5 \times 10^6$  Hz, respectively, more than six orders of magnitude smaller. Quantitative agreement is only slightly better for  $K_{0.3}MoO_3$ . Using the data of Mihaly *et al.* and Itkis *et al.*,<sup>16</sup> the predicted drift frequencies near  $E = E_T^*$  are  $\omega_d^*/2\pi \approx 1.3 \times 10^{10}$  Hz and  $2.3 \times 10^8$  Hz at  $T = 40$  and  $30$  K, respectively. The measured values are only  $1.3 \times 10^6$  Hz and  $1.4 \times 10^5$  Hz, nearly four orders of magnitude smaller.

Using Littlewood's model, Baier and Wonneberger<sup>19</sup> have calculated that the effective phason damping is proportional to the quasiparticle resistance at low frequencies, and that it crosses over to a much smaller value not at  $\omega_r$ , but a much lower frequency  $\omega_{peak} \propto \sigma_n$ , corresponding to the frequency of the peak in the imaginary part of the CDW dielectric constant.<sup>20</sup> Wonneberger has thus suggested<sup>21</sup> that  $\omega_d^* = \omega_{peak}$  may be the relevant criterion for determining  $E_T^*$ . Although  $\omega_{peak}$  is difficult to measure in NbSe<sub>3</sub>, from the  $K_{0.3}MoO_3$  data of Mihaly, Kim, and Gruner and Cava *et al.*,<sup>20</sup>  $\omega_{peak}/2\pi \approx 10^2$  Hz at  $T = 40$  K, eight orders of magnitude smaller than  $\omega_r$ , and four orders of magnitude smaller than the measured  $\omega_d^*$

value.

Do these quantitative discrepancies rule out the CDW-normal-carrier interaction as the origin of switching and related low-temperature effects in NbSe<sub>3</sub> and K<sub>0.3</sub>MoO<sub>3</sub>? First, we note that Littlewood's model has also successfully accounted for the qualitative features of the temperature- and frequency-dependent CDW dielectric constant in the semiconducting materials.<sup>9</sup> However, Littlewood's prediction for  $\omega_{\text{peak}}$  is four orders of magnitude larger than the measured value in K<sub>0.3</sub>MoO<sub>3</sub>;<sup>20</sup> calculations by Baier and Wonneberger<sup>19</sup> yield better agreement. Second, the qualitative success of Littlewood's model in accounting for dc properties follows immediately from the assumptions (1) that the CDW damping is proportional to  $\sigma_n$  at low frequencies; and (2) that the damping decreases above a frequency  $\omega_d^* \propto \sigma_n$ . Any model with a CDW damping of this form should yield the same qualitative agreement. In the absence of plausible alternative mechanisms for such a damping, we believe that the qualitative successes of Littlewood's model justify further efforts toward obtaining quantitative agreement.

Finally, we note that behavior very similar to that discussed here has been observed in the sliding spin-

density-wave (SDW) compound (TMTSF)<sub>2</sub>PF<sub>6</sub> by Mihaly, Kim, and Gruner.<sup>22</sup> In particular, the SDW conductance roughly scales with the normal conductance at low fields, and exhibits a large increase at high fields. Mihaly *et al.* proposed that the latter increase might arise from SDW tunneling. We suggest that tunneling is not involved, and that the corresponding SDW and CDW phenomena have a common explanation.

In conclusion, we have shown that switching in NbSe<sub>3</sub> is a bulk phenomenon and is intrinsic to CDW dynamics. We have emphasized the strong analogy between the general features of low-temperature CDW transport in NbSe<sub>3</sub> and those observed in the semiconducting CDW materials. These features are qualitatively consistent with treatments of the Fukuyama-Lee-Rice model which include CDW-normal-carrier interactions, but a quantitative theory of low-temperature dc transport is still needed.

We wish to thank W. Wonneberger, P. Littlewood, S. Coppersmith, M. Kvale, S. Ramakrishna, and C. Rappewicz for fruitful discussions. This work was supported by the NSF (Grant No. DMR-8958515).

<sup>1</sup>For comprehensive reviews of CDW's, see P. Monceau, in *Electronic Properties of Quasi-One-Dimensional Materials*, (Reidel, Dordrecht, 1985), Pt. II, p. 139; G. Gruner, *Rev. Mod. Phys.* **60**, 1129 (1988).

<sup>2</sup>A. Zettl and G. Gruner, *Phys. Rev. B* **26**, 2298 (1982).

<sup>3</sup>R. P. Hall, M. F. Hundley, and A. Zettl, *Phys. Rev. B* **38**, 13 002 (1988).

<sup>4</sup>M. P. Everson and R. V. Coleman, *Phys. Rev. B* **28**, 6659 (1984).

<sup>5</sup>K. Svoboda, A. Zettl, and M. S. Sherwin, *Solid State Commun.* **70**, 859 (1989).

<sup>6</sup>R. P. Hall, M. F. Hundley, and A. Zettl, *Phys. Rev. Lett.* **56**, 2399 (1986).

<sup>7</sup>M. Inui, R. P. Hall, S. Doniach, and A. Zettl, *Phys. Rev. B* **38**, 13047 (1988); C. M. Marcus, S. H. Strogatz, and R. M. Westervelt, *ibid.* **40**, 5588 (1989).

<sup>8</sup>B. Joos and D. Murray, *Phys. Rev. B* **29**, 1094 (1984); L. Mihaly, T. Chen, and G. Gruner, *Solid State Commun.* **61**, 751 (1987).

<sup>9</sup>P. B. Littlewood, *Solid State Commun.* **65**, 1347 (1988); *Synth. Metals* **29**, F531 (1989).

<sup>10</sup>E. Sweetland, C.-Y. Tsai, B. A. Wintner, J. D. Brock, and R. E. Thorne, *Phys. Rev. Lett.* **65**, 3165 (1990).

<sup>11</sup>J. McCarten, M. Maher, T. L. Adelman, and R. E. Thorne, *Phys. Rev. Lett.* **63**, 2841 (1989); J. McCarten *et al.*, *Phys. Rev. B* **46**, 4456 (1992).

<sup>12</sup>J. C. Gill, *J. Phys. C* **19**, 6589 (1986); P. Monceau, M. Renard, J. Richard, and M. C. Saint-Lager, *Physica* **143B**, 64 (1986); M. P. Maher, T. L. Adelman, S. Ramakrishna, J. P. McCarten, D. A. DiCarlo, and R. E. Thorne, *Phys. Rev. Lett.* **68**, 3084 (1992).

<sup>13</sup>S. Ramakrishna, M. P. Maher, V. Ambegaokar, and U. Eckern, *Phys. Rev. Lett.* **68**, 2066 (1992).

<sup>14</sup>Multiple switches may arise from the thickness dependence of  $E_T^*$ . The cross-sectional shape of all crystals varies along

their lengths, and many crystals crack over finite lengths along the whisker axis when they are cut, contacted, or subjected to thermal strains, resulting in variations in effective thickness.

<sup>15</sup>A. Fournel, J. P. Sorbier, M. Konczykowski, and P. Monceau, *Phys. Rev. Lett.* **57**, 2199 (1986); T. Ekino and J. Akimitsu, *Jpn. J. Appl. Phys.* **26**, 625 (1987). Reported values of  $2\Delta$  were 810 and 844 K, respectively.

<sup>16</sup>R. M. Fleming, R. J. Cava, L. F. Schneemeyer, E. A. Rietman, and R. G. Dunn, *Phys. Rev. B* **33**, 5450 (1986); G. Mihaly, P. Beauchene, J. Marcus, J. Dumas, and C. Schlenker, *ibid.* **37**, 1047 (1988); G. Mihaly, T. Chen, T. W. Kim, and G. Gruner *ibid.* **38**, 3602 (1988); A. Maeda, M. Notomi, and K. Uchinokura, *ibid.* **42**, 3290 (1990); M. E. Itkis and F. Ya. Nad, *Synth. Metals* **41-43**, 4037 (1991).

<sup>17</sup>F. Levy, M. Sherwin, F. Abraham, and K. Wiesenfeld [*Phys. Rev. Lett.* **68**, 2968 (1992)] have recently reported 1D simulations which predict that  $E_T$  evolves continuously into  $E_T^*$  with decreasing temperature (i.e., that  $E_T$  and  $E_T^*$  are not distinct) and that the CDW conductivity above  $E_T$  does not scale with  $\sigma_n$ , contrary to experiment. Their model is identical to Littlewood's model, and their simulation results are consistent with Littlewood's approximate analytic solution for 1D.

<sup>18</sup>N. P. Ong and J. W. Brill, *Phys. Rev. B* **18**, 5265 (1978); **18**, 5272 (1978).

<sup>19</sup>T. Baier and W. Wonneberger, *Solid State Commun.* **72**, 773 (1989).

<sup>20</sup>G. Mihaly, T. W. Kim, and G. Gruner, *Phys. Rev. B* **39**, 13 009 (1989); R. J. Cava, R. M. Fleming, P. Littlewood, E. A. Rietman, L. F. Schneemeyer, and R. G. Dunn, *ibid.* **30**, 3228 (1984).

<sup>21</sup>W. Wonneberger (private communication).

<sup>22</sup>G. Mihaly, Y. Kim, and G. Gruner, *Phys. Rev. Lett.* **67**, 2712 (1991).